- **Controlled Baseline** 
  - One Assembly/Test Site, One Fabrication
- **Enhanced Diminishing Manufacturing** Sources (DMS) Support
- **Enhanced Product-Change Notification**
- Qualification Pedigree<sup>†</sup>
- **Member of the Texas Instruments** Widebus™ Family
- **UBT™** Transceiver Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, or **Clocked Modes**
- **OEC™** Circuitry Improves Signal Integrity and Reduces Electromagnetic Interference (EMI)
- Compliant With VME64, 2eVME, and 2eSST **Protocols**
- **Bus Transceiver Split LVTTL Port Provides** Feedback Path for Control and Diagnostics Monitoring
- I/O Interfaces Are 5-V Tolerant
- B-Port Outputs (-48 mA/64 mA)
- Y and A-Port Outputs (-12 mA/12 mA)
- Ioff, Power-Up 3-State, and BIAS VCC Support Live Insertion
- **Bus Hold on 3A-Port Data Inputs**
- 26- $\Omega$  Equivalent Series Resistor on 3A Ports and Y Outputs
- Flow-Through Architecture Facilitates **Printed Circuit Board Layout**
- Distributed V<sub>CC</sub> and GND Pins Minimize **High-Speed Switching Noise**
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- **ESD Protection Exceeds JESD 22** 
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)

(101 11211)							
1OEBY	1 U	48	10EAB				
1A [	2	47	V <sub>CC</sub>				
1Y 🛚	3	46	1B				
GND [	4	45	GND				
2A 🛚	5		BIAS V <sub>CC</sub>				
2Y [	6		2B				
v <sub>cc</sub> [	7	42	V <sub>CC</sub>				
2OEBY		41					
3A1 [	9	40	3B1				
GND [	10	39	GND				
LE [	11	38	$V_{CC}$				
3A2 [	12	37	3B2				
3A3 [	13	36	3B3				
OE [	14	35	V <sub>CC</sub>				
GND [	15	34	GND				
3A4 [	16	33	3B4				
CLKBA [	17	32	CLKAB				
v <sub>cc</sub> [	18	31	$V_{CC}$				
3A5 [	19	30	3B5				
3A6 [	20	29	3B6				
GND [	21	28	GND				
3A7 [	22	27	3B7				
3A8 [	23	26	3B8				
DIR [	24	25	$V_{CC}$				

**DGG OR DGV PACKAGE** 

(TOP VIEW)

<sup>†</sup> Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.



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### description/ordering information

The SN74CVMEH22501A-EP 8-bit universal bus transceiver has two integral 1-bit three-wire bus transceivers and is designed for 3.3-V V<sub>CC</sub> operation with 5-V tolerant inputs. The UBT™ transceiver allows transparent, latched, and flip-flop modes of data transfer, and the separate LVTTL input and outputs on the bus transceivers provide a feedback path for control and diagnostics monitoring. This device provides a high-speed interface between cards operating at LVTTL logic levels and VME64, VME64x, or VME320<sup>†</sup> backplane topologies.

The SN74CVMEH22501A-EP is pin-for-pin capatible to the VMEH22501, but operates at a wider operating temperature (-40°C to 85°C) range.

High-speed backplane operation is a direct result of the improved OEC™ circuitry and high drive that has been designed and tested into the VME64x backplane model. The B-port I/Os are optimized for driving large capacitive loads and include pseudo-ETL input thresholds (one-half  $V_{CC}$   $\pm 50$  mV) for increased noise immunity. These specifications support the 2eVME protocols in VME64x (ANSI/VITA 1.1) and 2eSST protocols in VITA 1.5. With proper design of a 21-slot VME system, a designer can achieve 320-Mbyte transfer rates on linear backplanes and, possibly, 1-Gbyte transfer rates on the VME320 backplane.

All inputs and outputs are 5-V tolerant and are compatible with TTL and 5-V CMOS inputs.

Active bus-hold circuitry holds unused or undriven 3A-port inputs at a valid logic state. Bus-hold circuitry is not provided on 1A or 2A inputs, any B-port input, or any control input. Use of pullup or pulldown resistors with the bus-hold circuitry is not recommended.

This device is fully specified for live-insertion applications using I<sub>off</sub>, power-up 3-state, and BIAS V<sub>CC</sub>. The I<sub>off</sub> circuitry prevents damaging current to backflow through the device when it is powered off/on. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict. The BIAS V<sub>CC</sub> circuitry precharges and preconditions the B-port input/output connections, preventing disturbance of active data on the backplane during card insertion or removal, and permits true live-insertion capability.

When V<sub>CC</sub> is between 0 and 1.5 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V, output-enable (OE and OEBY) inputs should be tied to V<sub>CC</sub> through a pullup resistor and output-enable (OEAB) inputs should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the drive capability of the device connected to this input.

#### ORDERING INFORMATION

TA	PACKAGE <sup>‡</sup>		ORDERABLE PART NUMBER	TOP-SIDE MARKING	
-40°C to 85°C	TSSOP – DGG	Tape and reel	CVMEH22501AIDGGREP	VMEH22501EP	
-40 C 10 65 C	TVSOP - DGV	Tape and reel	CVMEH22501AIDGVREP	VK501AEP	

<sup>‡</sup>Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



<sup>&</sup>lt;sup>†</sup> VME320 is a patented backplane construction by Arizona Digital, Inc.

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	GQL PACKAGE (TOP VIEW)						
	_1	2	3	4	5	6	
Α				$\bigcirc$	$\bigcirc$	$\bigcirc$	•
В		$) \subset$	$\bigcirc$	$\bigcirc$	$\bigcirc$	$\bigcirc$	
С		$) \subset$	$\bigcirc$	$\bigcirc$	$\bigcirc$	$\bigcirc$	
D		$) \subset$		$\bigcirc$	$\bigcirc$	$\bigcirc$	
Е		$) \subset$	)		$\bigcirc$	$\bigcirc$	
F		$) \subset$	)		$\bigcirc$	$\bigcirc$	
G		$) \subset$		$\bigcirc$	$\bigcirc$	$\bigcirc$	
Н	C	$) \subset$		$\bigcirc$	$\bigcirc$	$\bigcirc$	
J		$) \subset$		$\bigcirc$	$\bigcirc$	$\bigcirc$	
K	$\bigcup$	$) \subset$		$\bigcirc$	$\bigcirc$	$\bigcirc$	

### terminal assignments

	1	2	3	4	5	6
Α	1OEBY	NC	NC	NC	NC	10EAB
В	1Y	1A	GND	GND	VCC	1B
С	2Y	2A	Vcc	Vcc	BIAS V <sub>CC</sub>	2B
D	3A1	2OEBY	GND	GND	20EAB	3B1
Е	3A2	LE			VCC	3B2
F	3A3	OE			VCC	3B3
G	3A4	CLKBA	GND	GND	CLKAB	3B4
Н	3A5	3A6	Vcc	Vcc	3B6	3B5
J	3A7	3A8	GND	GND	3B8	3B7
K	DIR	NC	NC	NC	NC	Vcc

NC - No internal connection

### functional description

The SN74CVMEH22501A–EP is a high-drive (–48/64 mA), 8-bit UBT transceiver containing D-type latches and D-type flip-flops for data-path operation in transparent, latched, or flip-flop modes. Data transmission is true logic. The device is uniquely partitioned as 8-bit UBT transceivers with two integrated 1-bit three-wire bus transceivers.

### functional description for two 1-bit bus transceivers

The OEAB inputs control the activity of the 1B or 2B port. When OEAB is high, the B-port outputs are active. When OEAB is low, the B-port outputs are disabled.

Separate 1A and 2A inputs and 1Y and 2Y outputs provide a feedback path for control and diagnostics monitoring. The OEBY inputs control the 1Y or 2Y outputs. When OEBY is low, the Y outputs are active. When OEBY is high, the Y outputs are disabled.

The OEBY and OEAB inputs can be tied together to form a simple direction control where an input high yields A data to B bus and an input low yields B data to Y bus.

### 1-BIT BUS TRANSCEIVER FUNCTION TABLE

INP	UTS	OUTPUT	MODE
OEAB	OEBY	OUTPUT	MODE
L	Н	Z	Isolation
Н	Н	A data to B bus	Torre del con
L	L	B data to Y bus	True driver
Н	L	A data to B bus, B data to Y bus	True driver with feedback path



### functional description for 8-bit UBT transceiver

The 3A and 3B data flow in each direction is controlled by the  $\overline{OE}$  and direction-control (DIR) inputs. When  $\overline{OE}$  is low, all 3A- or 3B-port outputs are active. When OE is high, all 3A- or 3B-port outputs are in the high-impedance

#### **FUNCTION TABLE**

INP	UTS	OUTDUT		
ŌĒ	DIR	OUTPUT		
Н	Χ	Z		
L	Н	3A data to 3B bus		
L	L	3B data to 3A bus		

The UBT transceiver functions are controlled by latch-enable (LE) and clock (CLKAB and CLKBA) inputs. For 3A-to-3B data flow, the UBT operates in the transparent mode when LE is high. When LE is low, the 3A data is latched if CLKAB is held at a high or low logic level. If LE is low, the 3A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB.

The UBT transceiver data flow for 3B to 3A is similar to that of 3A to 3B, but uses CLKBA.

#### **UBT TRANSCEIVER FUNCTION TABLE**<sup>†</sup>

	INPUTS			OUTPUT	
OE	LE	CLKAB	3A	3B	MODE
Н	Х	Χ	Χ	Z	Isolation
L	L	Н	Х	в <sub>0</sub> ‡	
L	L	L	Χ	в <sub>0</sub> ‡ в <sub>0</sub> §	Latched storage of 3A data
L	Н	Х	L	L	To a to a const
L	Н	Χ	Н	Н	True transparent
L	L	$\uparrow$	L	L	Ole also de terre no est OA de te
L	L	1	Н	Н	Clocked storage of 3A data

<sup>†3</sup>A-to-3B data flow is shown; 3B-to-3A data flow is similar, but uses CLKBA.

The UBT transceiver can replace any of the functions shown in Table 1.

Table 1. SN74CVMEH22501A-EP UBT Transceiver Replacement Functions

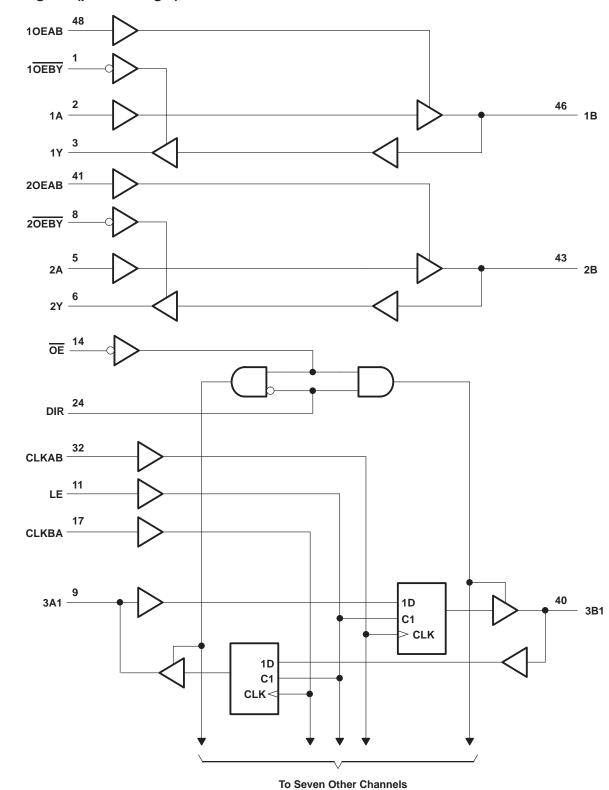
FUNCTION	8 BIT
Transceiver	'245, '623, '645
Buffer/driver	'241, '244, '541
Latched transceiver	'543
Latch	'373, '573
Registered transceiver	'646, '652
Flip-flop	'374, '574
SN74CVMEH22501A-EF replaces all above	



<sup>&</sup>lt;sup>‡</sup> Output level before the indicated steady-state input conditions were established, provided that CLKAB was high before LE went low

<sup>§</sup> Output level before the indicated steady-state input conditions were established

### logic diagram (positive logic)



Pin numbers shown are for the DGG and DGV packages.



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V <sub>CC</sub> and BIAS V <sub>CC</sub>	
Voltage range applied to any output in the high-impedance	
or power-off state, V <sub>O</sub> (see Note 1)	
Voltage range applied to any output in the high or low state, VO	
(see Note 1): 3A port or Y output	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
B port	–0.5 V to 4.6 V
Output current in the low state, IO: 3A port or Y output	50 mA
B port	100 mA
Output current in the high state, IO: 3A port or Y output	
B port	
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ ): B port	
Package thermal impedance, θ <sub>JA</sub> (see Note 2): DGG package	70°C/W
DGV package	
Storage temperature range, T <sub>Stq</sub> (see Note 3)	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
  - 2. The package thermal impedance is calculated in accordance with JESD 51-7.
  - 3. Long-term high-temperature storage and/or extended use at maximum recommended operating conditions may result in a reduction of overall device life. See http://www.ti.com/ep\_quality for additional information on enhanced plastic packaging.

### recommended operating conditions (see Notes 4 and 5)

			MIN	TYP	MAX	UNIT	
V <sub>CC</sub> , BIAS V <sub>CC</sub>	Supply voltage		3.15	3.3	3.45	V	
	la mada and la ma	Control inputs or A port		Vcc	5.5	.,	
VI	Input voltage	B port		Vcc	5.5	V	
V	I Pale I seed Construction	Control inputs or A port	2			Ι.,	
VIH	High-level input voltage	B port	0.5 V <sub>CC</sub> + 50 mV			V	
	Lauren in anti-order and	Control inputs or A port			0.8	.,	
$V_{IL}$	Low-level input voltage	B port			0.5 V <sub>CC</sub> – 50 mV	V	
lıĸ	Input clamp current				-18	mA	
	I Pale I and autout annual	3A port and Y output			-12	4	
ЮН	High-level output current	B port			-48	mA	
		3A port and Y output			12		
lOL	Low-level output current	B port			64	mA	
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled			10	ns/V	
Δt/ΔV <sub>CC</sub>	Power-up ramp rate		20			μs/V	
TA	Operating free-air temperature		-40		85	°C	

- NOTES: 4. All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.
  - 5. Proper connection sequence for use of the B-port I/O precharge feature is GND and BIAS V<sub>CC</sub> = 3.3 V first, I/O second, and V<sub>CC</sub> = 3.3 V last, because the BIAS V<sub>CC</sub> precharge circuitry is disabled when any V<sub>CC</sub> pin is connected. The control inputs can be connected anytime, but normally are connected during the I/O stage. If B-port precharge is not required, any connection sequence is acceptable, but generally, GND is connected first.



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## electrical characteristics over recommended operating free-air temperature range for A and B ports (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	MIN	TYP†	MAX	UNIT
VIK		V <sub>CC</sub> = 3.15 V,	I <sub>I</sub> = -18 mA			-1.2	V
	3A port, any B port, and Y outputs	V <sub>CC</sub> = 3.15 V to 3.45 V,	I <sub>OH</sub> = -100 μA	V <sub>CC</sub> - 0.2			
.,	OA mant and Wassington	V 0.45.V	$I_{OH} = -6 \text{ mA}$	2.4			
VOH	3A port and Y outputs	V <sub>CC</sub> = 3.15 V	$I_{OH} = -12 \text{ mA}$	2			V
	Any Dinort	V 245V	$I_{OH} = -24 \text{ mA}$	2.4			
	Any B port	V <sub>CC</sub> = 3.15 V	$I_{OH} = -48 \text{ mA}$	2			
	3A port, any B port, and Y outputs	$V_{CC} = 3.15 \text{ V to } 3.45 \text{ V},$	I <sub>OL</sub> = 100 μA			0.2	
	OA mant and Wassington	V 0.45.V	I <sub>OL</sub> = 6 mA			0.55	8 V 4 5
VOL	3A port and Y outputs	$V_{CC} = 3.15 \text{ V}$	I <sub>OL</sub> = 12 mA			8.0	
	Any B port		I <sub>OL</sub> = 24 mA			0.4	
		V <sub>CC</sub> = 3.15 V	$I_{OL} = 48 \text{ mA}$			0.55	
			$I_{OL} = 64 \text{ mA}$			0.6	
1.	Control inputs,	$V_{CC} = 3.45 \text{ V},$	$V_I = V_{CC}$ or GND			±1	^
I <sub>I</sub>	1A and 2A	$V_{CC} = 0 \text{ or } 3.45 \text{ V},$	V <sub>I</sub> = 5.5 V			5	μΑ
I <sub>OZH</sub> ‡	3A port, any B port, and Y outputs	$V_{CC} = 3.45 \text{ V},$	$V_O = V_{CC}$ or 5.5 V			5	μΑ
	3A port and Y outputs					-5	
lozL‡	Any B port	$V_{CC} = 3.45 \text{ V},$	$V_O = GND$			-20	μΑ
l <sub>off</sub>		$V_{CC} = 0$ , BIAS $V_{CC} = 0$ ,	$V_{I}$ or $V_{O} = 0$ to 5.5 V			±10	μΑ
I <sub>BHL</sub> §	3A port	V <sub>CC</sub> = 3.15 V,	V <sub>I</sub> = 0.8 V	75			μΑ
I <sub>BHH</sub> ¶	3A port	V <sub>CC</sub> = 3.15 V,	V <sub>I</sub> = 2 V	-75			μΑ
I <sub>BHLO</sub> #	3A port	V <sub>CC</sub> = 3.45 V,	$V_I = 0$ to $V_{CC}$	500			μΑ
Івнно	3A port	V <sub>CC</sub> = 3.45 V,	$V_I = 0$ to $V_{CC}$	-500			μΑ
I <sub>OZ(PU/F</sub>	PD)*	$V_{CC} \le 1.3 \text{ V}, V_{O} = 0.5 \text{ V to V}$ $V_{I} = \text{GND or } V_{CC}, \overline{\text{OE}} = \text{don'}$	CC, t care		_	±10	μΑ

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



For I/O ports, the parameters IOZH and IOZL include the input leakage current.

<sup>§</sup> The bus-hold circuit can sink at least the minimum low sustaining current at V<sub>IL</sub> max. I<sub>BHL</sub> should be measured after lowering V<sub>IN</sub> to GND, then raising it to V<sub>IL</sub> max.

The bus-hold circuit can source at least the minimum high sustaining current at V<sub>IH</sub> min. I<sub>BHH</sub> should be measured after raising V<sub>IN</sub> to V<sub>CC</sub>, then lowering it to V<sub>IH</sub> min.

<sup>#</sup> An external driver must source at least IBHLO to switch this node from low to high.

An external driver must sink at least IBHHO to switch this node from high to low.

<sup>\*</sup>High-impedance state during power up or power down

### electrical characteristics over recommended operating free-air temperature range for A and B ports (unless otherwise noted) (continued)

	PARAMETER	TEST CO	NDITIONS	MIN TYPT	MAX	UNIT	
			Outputs high		30		
ICC		$V_{CC} = 3.45 \text{ V}, I_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND}$	Outputs low		30	mA	
		V = VCC 01 014B	Outputs disabled		30		
		$V_{CC} = 3.45 \text{ V}, I_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND},$	Outputs enabled	76		μΑ/ clock	
ICCD		One data input switching at one-half clock frequency, 50% duty cycle	Outputs disabled	19		MHz/ input	
ΔlCC	]	$V_{CC}$ = 3.15 V to 3.45 V, One Other inputs at $V_{CC}$ or GND			750	μΑ	
_	1A and 2A inputs	V 0.45 V - 7 0		2.8			
Ci	Control inputs	V <sub>I</sub> = 3.15 V or 0		2.6		pF	
Со	1Y or 2Y outputs	V <sub>O</sub> = 3.15 V or 0		5.6		pF	
C.	3A port	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	\/o = 2.2\/ or 0	7.9		n.E	
C <sub>io</sub>	Any B port	$V_{CC} = 3.3 \text{ V},$	$V_0 = 3.3 \text{ V or } 0$	11	12.5	pF	

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

### live-insertion specifications over recommended operating free-air temperature range for B port

PARAMETER	TEST CONDITIONS			MIN	TYP <sup>†</sup>	MAX	UNIT
I (DIAC)/)	$V_{CC} = 0$ to 3.15 V,	BIAS $V_{CC} = 3.15 \text{ V to } 3.45 \text{ V},  I_{O(DC)} = 0$				5	mA
I <sub>CC</sub> (BIAS V <sub>CC</sub> )	$V_{CC} = 3.15 \text{ V to } 3.45 \text{ V}^{\ddagger},$	BIAS $V_{CC} = 3.15 \text{ V to } 3.45 \text{ V},$	$I_{O(DC)} = 0$			10	μΑ
VO	$V_{CC} = 0$ ,	BIAS V <sub>CC</sub> = 3.15 V to 3.45 V		1.3	1.5	1.7	V
		$V_{O} = 0$ ,	BIAS V <sub>CC</sub> = 3.15 V	-20		-100	
IO	VCC = 0	V <sub>O</sub> = 3 V,	BIAS V <sub>CC</sub> = 3.15 V	20		100	μΑ

<sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. ‡  $V_{CC}$  - 0.5 V < BIAS  $V_{CC}$ 



This is the increase in supply current for each input that is at the specified TTL voltage level, rather than VCC or GND.

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## timing requirements over recommended operating conditions for UBT transceiver (unless otherwise noted) (see Figures 1 and 2)

				MIN	MAX	UNIT
f <sub>clock</sub>	Clock frequency				120	MHz
	Pulse duration	LE high		2.5		20
t <sub>W</sub>	Pulse duration	CLK high or low		3		ns
		24 hofore CLVA	Data high	2.1		
		3A before CLK↑	Data low	2.2		
		3A before LE↓	CLK high	2		
	Outers there	SA belore LE↓	CLK low	2		
tsu	t <sub>su</sub> Setup time	OD haters OUK	Data high	2.5		ns
		3B before CLK↑	Data low	2.7		
		OD before LE	CLK high	2		
		3B before LE↓	CLK low	2		
		0.4 - 4 - 7 - 0   14 1	Data high	0		
		3A after CLK↑	Data low	0		
		6 . <del>-</del> -1	CLK high	1		
		3A after LE↓	CLK low	1		
<sup>t</sup> h	Hold time		Data high	0		ns
		3B after CLK↑	Data low	0		
			CLK high	1		
		3B after LE↓	CLK low	1		

# switching characteristics over recommended operating conditions for bus transceiver function (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
<sup>t</sup> PLH	44.0004	4B at 2B	4.5		9.2	
t <sub>PHL</sub>	1A or 2A	1B or 2B	4.2		7.8	ns
<sup>t</sup> PLH	1A or 2A	47/ 27/ 27/	6.2		14.5	
<sup>t</sup> PHL	TA OF ZA	1Y or 2Y	6.1		13	ns
<sup>t</sup> PZH	OEAB	45 65	3.6		8.1	
<sup>t</sup> PZL	OEAB	1B or 2B	3.4		7.8	ns
<sup>t</sup> PHZ	OEAB	1B or 2B	3.3		9.7	20
t <sub>PLZ</sub>	OEAB	1B 01 2B	1.8		4.8	ns
t <sub>r</sub>	Transition time, B	3 port (10%–90%)		4.3		ns
tf	Transition time, B	s port (90%–10%)		4.3		ns
<sup>t</sup> PLH	4D of 0D	47, 07,	1.6		5.6	
t <sub>PHL</sub>	1B of 2B	1Y or 2Y	1.6		5.6	ns
<sup>t</sup> PZH	<del>OEBY</del>	4V on 9V	1.2		5.6	
t <sub>PZL</sub>	OEBY	1Y or 2Y	1.8		4.9	ns
<sup>t</sup> PHZ	<del>OEBY</del>	47 97	0.9		5.4	
t <sub>PLZ</sub>	JEBI	1Y or 2Y	1.4		4.5	ns

### switching characteristics over recommended operating conditions for UBT transceiver (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
f <sub>max</sub>			120			MHz
<sup>t</sup> PLH	24	0.0	4.8		9.5	
<sup>t</sup> PHL	3A	3B	4.5		8.3	ns
t <sub>PLH</sub>	LE	ap.	5.2		10.6	
<sup>t</sup> PHL	LE	3B	4.7		8.7	ns
<sup>t</sup> PLH	CLKAB	3B	5.4		10.5	20
<sup>t</sup> PHL	CLKAB	ЭВ	4.2		8.4	ns
<sup>t</sup> PZH	ŌĒ	an.	4.2		9.3	
<sup>t</sup> PZL	OE	3B	2.8		8.5	ns
<sup>t</sup> PHZ	ŌĒ	3B	4.2		9.3	
tPLZ			2.4		5.7	ns
t <sub>r</sub>	Transition time, B	port (10%–90%)		4.3		ns
t <sub>f</sub>	Transition time, B	port (90%–10%)		4.3		ns
<sup>t</sup> PLH	an.		1.5		5.9	
<sup>t</sup> PHL	3B	3A	1.7		5.9	ns
<sup>t</sup> PLH	LE	24	1.7		5.9	
<sup>t</sup> PHL	LE	3A	1.7		5.9	ns
<sup>t</sup> PLH	CLKDA	0.4	1.1		5.5	
<sup>t</sup> PHL	CLKBA	3A	1.4		5.5	ns
<sup>t</sup> PZH	<del></del>	0.4	1.5		6.2	
tPZL	ŌĒ	3A	2.1		5.5	ns
t <sub>PHZ</sub>	ŌĒ	3A	0.8		6.2	
<sup>t</sup> PLZ	OE .	JA.	2.3		5.6	ns

## skew characteristics for bus transceiver for specific worst-case $V_{CC}$ and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT	
<sup>t</sup> sk(LH)	1A or 2A	4D or 2D		8.0		
<sup>t</sup> sk(HL)	1A or 2A 1B or 2B			0.7	ns	
<sup>t</sup> sk(LH)	1B or 2B	1Y or 2Y		0.7		
<sup>t</sup> sk(HL)	16 01 26	11 0121		0.7	ns	
4 <del>†</del>	1A or 2A	1B or 2B		3.9	20	
t <sub>sk(t)</sub> †	1B or 2B	1Y or 2Y		1.5	ns	
t., ,	1A or 2A	1B or 2B		3.6	20	
<sup>t</sup> sk(pp)	1B or 2B	1Y or 2Y		1.4	ns	

<sup>†</sup> t<sub>sk(t)</sub> – Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case VCC and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [tsk(t)].



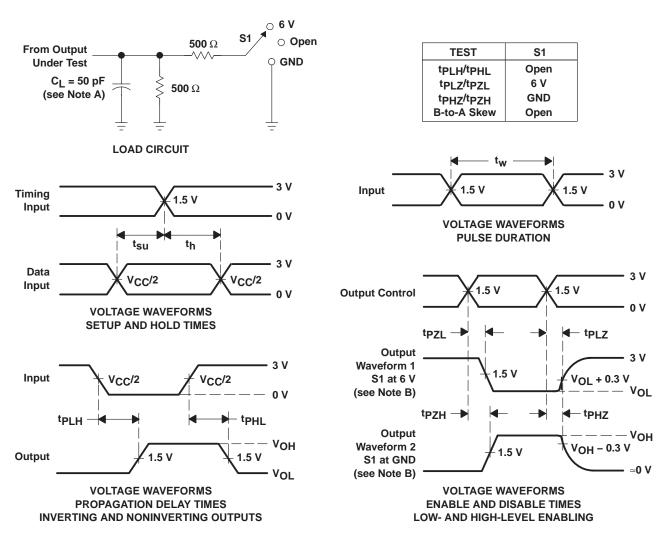
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# skew characteristics for UBT for specific worst-case $V_{CC}$ and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN MAX	UNIT	
<sup>t</sup> sk(LH)	- 3A	3B	1.4	ns	
<sup>t</sup> sk(HL)	SA	JD.	1.1	115	
t <sub>sk(LH)</sub>	CLKAR	20	0.8	ns	
<sup>t</sup> sk(HL)	CLNAB	CLKAB 3B			
<sup>t</sup> sk(LH)	20		0.7		
<sup>t</sup> sk(HL)	<b>3</b> B	3A		ns	
<sup>t</sup> sk(LH)	CLIVDA	2.4	0.7		
<sup>t</sup> sk(HL)	CLKBA	3A	0.6	ns	
	3A	3B	3.9		
+t	CLKAB	3B	3.9		
t <sub>sk(t)</sub> †	3B	3A	1.6	ns	
	CLKBA	3A	1.2		
	3A	3B	3.6		
	CLKAB	3B	3.5		
<sup>t</sup> sk(pp)	3B	3B 3A		ns	
	CLKBA	3A	1.2		

 $t_{sk(t)}$  – Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case  $v_{CC}$  and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [ $t_{sk(t)}$ ].

### PARAMETER MEASUREMENT INFORMATION A PORT



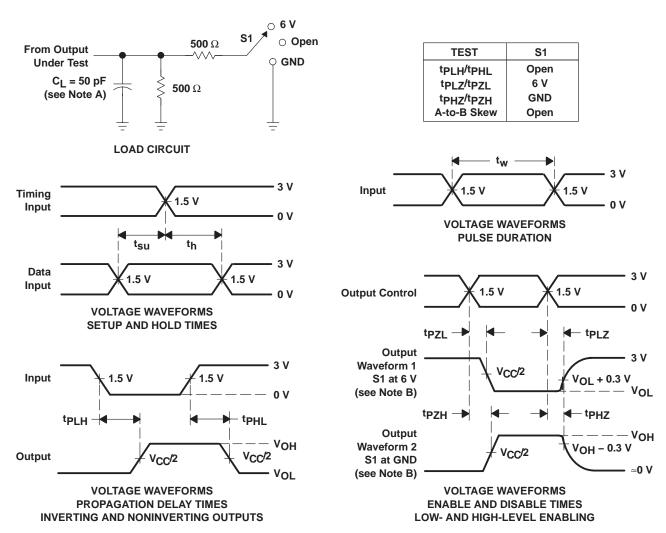
NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\approx$  10 MHz,  $Z_{\Omega}$  = 50  $\Omega$ ,  $t_{r}$   $\approx$  2 ns,  $t_{f}$   $\approx$  2 ns.
- D. The outputs are measured one at a time, with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



## PARAMETER MEASUREMENT INFORMATION B PORT



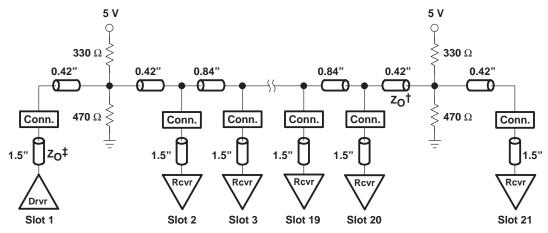
NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\approx$  10 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_f$   $\approx$  2 ns,  $t_f$   $\approx$  2 ns.
- D. The outputs are measured one at a time, with one transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms

### DISTRIBUTED-LOAD BACKPLANE SWITCHING CHARACTERISTICS

The preceding switching characteristics tables show the switching characteristics of the device into the lumped load shown in the parameter measurement information (PMI) (see Figures 1 and 2). All logic devices currently are tested into this type of load. However, the designer's backplane application probably is a distributed load. For this reason, this device has been designed for optimum performance in the VME64x backplane as shown in Figure 3.



<sup>&</sup>lt;sup>†</sup> Unloaded backplane trace natural impedence ( $Z_{\Omega}$ ) is 45  $\Omega$ . 45  $\Omega$  to 60  $\Omega$  is allowed, with 50  $\Omega$  being ideal.

Figure 3. VME64x Backplane

The following switching characteristics tables derived from TI-SPICE models show the switching characteristics of the device into the backplane under full and minimum loading conditions, to help the designer better understand the performance of the VME device in this typical backplane. See www.ti.com/sc/etl for more information.

driver in slot 11, with receiver cards in all other slots (full load)

## switching characteristics over recommended operating conditions for bus transceiver function (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP§	MAX	UNIT
<sup>t</sup> PLH	44 24	1B or 2B	5.9		8.5	
<sup>t</sup> PHL	1A or 2A		5.5		8.7	ns
t <sub>r</sub> ¶	Transition time, B	Transition time, B port (10%–90%)		8.6	11.4	ns
t <sub>f</sub> ¶	Transition time, B	3 port (90%–10%)	8.9	9	10.8	ns

<sup>§</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C. All values are derived from TI-SPICE models.

<sup>‡</sup> Card stub natural impedence ( $Z_O$ ) is 60  $\Omega$ .

 $<sup>\</sup>P$  All  $t_r$  and  $t_f$  times are taken at the first receiver.

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driver in slot 11, with receiver cards in all other slots (full load) (continued)

## switching characteristics over recommended operating conditions for UBT (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP†	MAX	UNIT
tPLH	24	an.	6.2		8.9	
t <sub>PHL</sub>	3A	3B	5.6		9	ns
tPLH	LE	3B	6.1		9.1	
<sup>t</sup> PHL	LE		5.6		9	ns
tPLH	CLKAB	3B	6.2		9.1	
t <sub>PHL</sub>	CLKAB		5.7		9	ns
t <sub>r</sub> ‡	Transition time, B port (10%-90%)		9	8.6	11.4	ns
t <sub>f</sub> ‡	Transition time, B	s port (90%–10%)	8.9	9	10.8	ns

<sup>&</sup>lt;sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C. All values are derived from TI-SPICE models.

### skew characteristics for bus transceiver for specific worst-case V<sub>CC</sub> and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN TYPT MAX	UNIT
<sup>t</sup> sk(LH)	1A or 2A	1B or 2B	2.5	
tsk(HL)	TA OF ZA	16 01 26	3	ns
t <sub>sk(t)</sub> §	1A or 2A	1B or 2B	1	ns
t <sub>sk(pp)</sub>	1A or 2A	1B or 2B	0.5 3.4	ns

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C. All values are derived from TI-SPICE models.

## skew characteristics for UBT for specific worst-case $V_{CC}$ and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN TYPT	MAX	UNIT
<sup>t</sup> sk(LH)	24	3B		2.4	
<sup>t</sup> sk(HL)	3A	)D		3.4	ns
<sup>t</sup> sk(LH)	CLKAB	an.		2.7	
tsk(HL)		3B		3.4	ns
. 8	3A	3B		1	
t <sub>sk(t)</sub> §	CLKAB	3B		1	ns
+ + / .	3A	3B	0.5	3.4	20
tsk(pp)	CLKAB	3B	0.6	3.5	ns

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. All values are derived from TI-SPICE models.

<sup>§</sup>  $t_{sk(t)}$  – Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case  $V_{CC}$  and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [ $t_{sk(t)}$ ].



<sup>‡</sup> All t<sub>r</sub> and t<sub>f</sub> times are taken at the first receiver.

<sup>§</sup> t<sub>sk(t)</sub> – Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V<sub>CC</sub> and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [t<sub>sk(t)</sub>].

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driver in slot 1, with one receiver in slot 21 (minimum load)

### switching characteristics over recommended operating conditions for bus transceiver function (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP <sup>†</sup>	MAX	UNIT
<sup>t</sup> PLH	44 24	1B or 2B	5.5		7.4	
<sup>t</sup> PHL	1A or 2A		5.3		7.4	ns
t <sub>r</sub> ‡	Transition time, B	Transition time, B port (10%–90%)		3.4	4.4	ns
t <sub>f</sub> ‡	Transition time, B	port (90%–10%)	3.7	3.4	4.8	ns

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C. All values are derived from TI-SPICE models.

### switching characteristics over recommended operating conditions for UBT (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	2.4	an.	5.8		7.9	
t <sub>PHL</sub>	3A	3B	5.5		7.7	ns
t <sub>PLH</sub>	LE	3B	5.9		8	
t <sub>PHL</sub>			5.5		7.8	ns
t <sub>PLH</sub>	CLKAB	3B	5.9		8.1	
<sup>t</sup> PHL	CLKAB		5.5		7.7	ns
t <sub>r</sub> ‡	Transition time, B port (10%-90%)		3.9	3.4	4.4	ns
t <sub>f</sub> ‡	Transition time, B	port (90%–10%)	3.7	3.4	4.8	ns

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. All values are derived from TI-SPICE models.

# skew characteristics for bus transceiver for specific worst-case $V_{CC}$ and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN TYPT	MAX	UNIT
<sup>t</sup> sk(LH)	1A or 2A	1B or 2B		1.7	20
<sup>t</sup> sk(HL)	TA OI ZA	10 01 20		2.1	ns
t <sub>sk(t)</sub> §	1A or 2A	1B or 2B		1	ns
<sup>t</sup> sk(pp)	1A or 2A	1B or 2B	0.2	2.1	ns

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C. All values are derived from TI-SPICE models.



<sup>‡</sup> All t<sub>r</sub> and t<sub>f</sub> times are taken at the first receiver.

<sup>‡</sup> All t<sub>r</sub> and t<sub>f</sub> times are taken at the first receiver.

<sup>§</sup> tsk(t) – Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case VCC and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [t<sub>Sk(t)</sub>].

driver in slot 1, with one receiver in slot 21 (minimum load) (continued)

skew characteristics for UBT for specific worst-case  $V_{CC}$  and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN TYPT MAX	UNIT
tsk(LH)	24	an.	2	
tsk(HL)	- 3A	3B	2.3	ns
tsk(LH)	OLKAD.	an.	2.1	
t <sub>sk(HL)</sub>	- CLKAB	3B	2.4	ns
4 <del>.</del> †	3A	3B	1	
t <sub>sk(t)</sub> ‡	CLKAB	3B	1	ns
+ + / >	3A	3B	0.2 2.5	
<sup>t</sup> sk(pp)	CLKAB	3B	0.2 2.9	ns

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. All values are derived from TI-SPICE models.

By simulating the performance of the device using the VME64x backplane (see Figure 3), the maximum peak current in or out of the B-port output, as the devices switch from one logic state to another, was found to be equivalent to driving the lumped load shown in Figure 4.

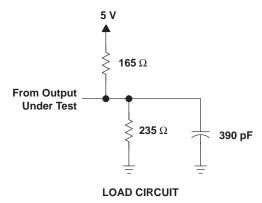


Figure 4. Equivalent AC Peak Output-Current Lumped Load

<sup>‡</sup>t<sub>sk(t)</sub> – Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V<sub>CC</sub> and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [t<sub>sk(t)</sub>].

### driver in slot 1, with one receiver in slot 21 (minimum load) (continued)

In general, the rise- and fall-time distribution is shown in Figure 5. Since VME devices were designed for use into distributed loads like the VME64x backplane (B/P), there are significant differences between low-to-high (LH) and high-to-low (HL) values in the lumped load shown in the PMI (see Figures 1 and 2).

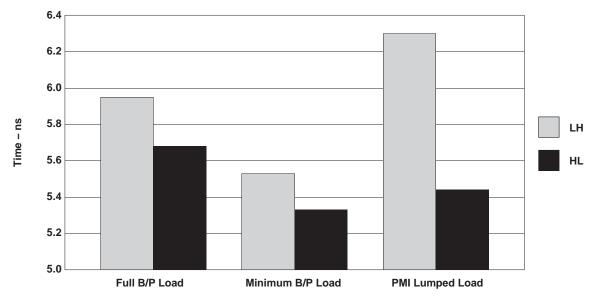
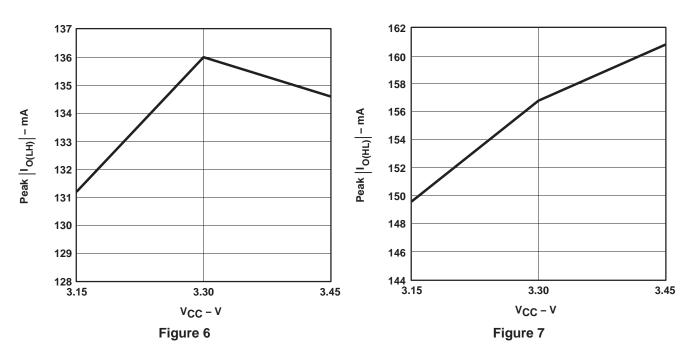


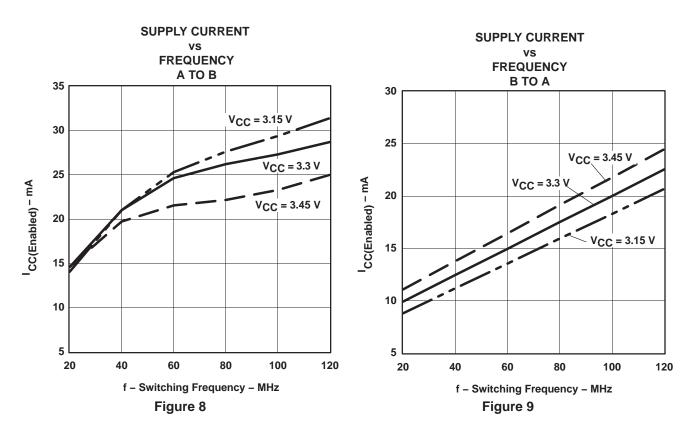
Figure 5

Characterization-laboratory data in Figures 6 and 7 show the absolute ac peak output current, with different supply voltages, as the devices change output logic state. A typical nominal process is shown to demonstrate the devices' peak ac output drive capability.



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### TYPICAL CHARACTERISTICS



### **TYPICAL CHARACTERISTICS**

# HIGH-LEVEL OUTPUT VOLTAGE vs HIGH-LEVEL OUTPUT CURRENT

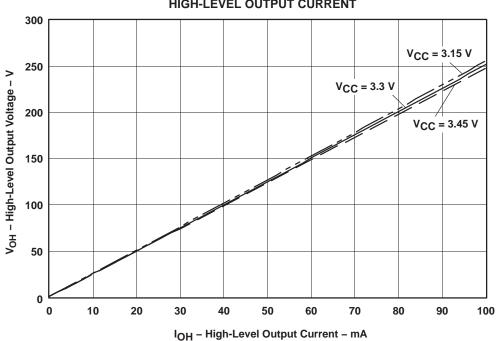


Figure 10.  $V_{OL}$  vs  $I_{OL}$ 

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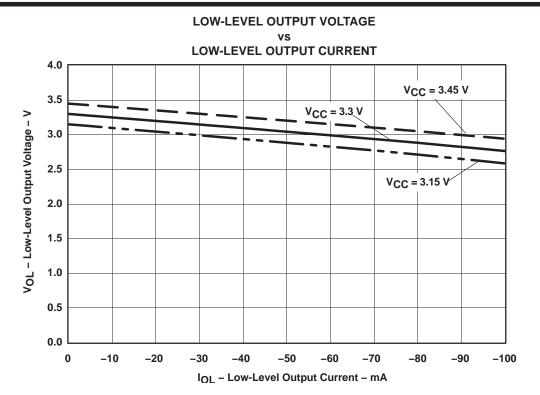


Figure 11. VOH vs IOH

### **VMEbus SUMMARY**

In 1981, the VMEbus was introduced as a backplane bus architecture for industrial and commercial applications. The data-transfer protocols used to define the VMEbus came from the Motorola™ VERSA bus architecture, which owed its heritage to the then recently introduced Motorola 68000 microprocessor. The VMEbus, when introduced, defined two basic data-transfer operations – single-cycle transfers consisting of an address and a data transfer, and a block transfer (BLT) consisting of an address and a sequence of data transfers. These transfers were asynchronous, using a master-slave handshake. The master puts address and data on the bus and waits for an acknowledgment. The selected slave either reads or writes data to or from the bus, then provides a data-acknowledge (DTACK\*) signal. The VMEbus system data throughput was 40 Mbyte/s. Previous to the VMEbus, it was not uncommon for the backplane buses to require elaborate calculations to determine loading and drive current for interface design. This approach made designs difficult and caused compatibility problems among manufacturers. To make interface design easier and to ensure compatibility, the developers of the VMEbus architecture defined specific delays based on a 21-slot terminated backplane and mandated the use of certain high-current TTL drivers, receivers, and transceivers.

In 1989, multiplexing block transfer (MBLT) effectively increased the number of bits from 32 to 64, thereby doubling the transfer rate. In 1995, the number of handshake edges was reduced from four to two in the double-edge transfer (2eVME) protocol, doubling the data rate again. In 1997, the VMEbus International Trade Association (VITA) established a task group to specify a synchronous protocol to increase data-transfer rates to 320 Mbyte/s, or more. The unreleased specification, VITA 1.5 [double-edge source synchronous transfer (2eSST)], is based on the asynchronous 2eVME protocol. It does not wait for acknowledgement of the data by the receiver and requires incident-wave switching. Sustained data rates of 1 Gbyte/s, more than ten times faster than traditional VME64 backplanes, are possible by taking advantage of 2eSST and the 21-slot VME320 star-configuration backplane. The VME320 backplane approximates a lumped load, allowing substantially higher-frequency operation over the VME64x distributed-load backplane. Traditional VME64 backplanes with no changes theoretically can sustain 320 Mbyte/s.



From BLT to 2eSST - A Look at the Evolution of VMEbus Protocols by John Rynearson, Technical Director, VITA, provides additional information on VMEbus and can be obtained at www.vita.com.

### maximum data transfer rates

	T0001 00V		DATA BITS	DATA TRANSFERS	PER SYSTEM	FREQUENCY (MHz)		
DATE	TOPOLOGY	PROTOCOL PER CYC		PER CLOCK CYCLE	(Mbyte/s)	BACKPLANE	CLOCK	
1981	VMEbus IEEE-1014	BLT	32	1	40	10	10	
1989	VME64	MBLT	64	1	80	10	10	
1995	VME64x	2eVME	64	2	160	10	20	
1997	VME64x	2eSST	64	2-No Ack	160-320	10–20	20–40	
1999	VME320	2eSST	64	2-No Ack	320–1000	20-62.5	40–125	

### applicability

Target applications for VME backplanes include industrial controls, telecommunications, simulation, high-energy physics, office automation, and instrumentation systems.







ti.com 18-Sep-2008

#### PACKAGING INFORMATION

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
CVMEH22501AIDGGREP	ACTIVE	TSSOP	DGG	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
CVMEH22501AIDGVREP	ACTIVE	TVSOP	DGV	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
V62/05606-01XE	ACTIVE	TSSOP	DGG	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
V62/05606-01YE	ACTIVE	TVSOP	DGV	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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#### OTHER QUALIFIED VERSIONS OF SN74VMEH22501A-EP:

Catalog: SN74VMEH22501A

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

www.ti.com 11-Aug-2009

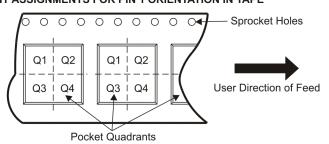
### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

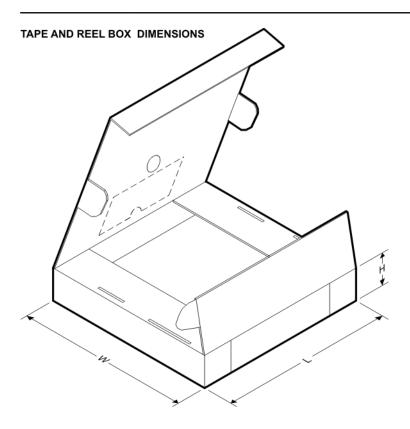
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CVMEH22501AIDGGREP	TSSOP	DGG	48	2000	330.0	24.4	8.6	15.8	1.8	12.0	24.0	Q1
CVMEH22501AIDGVREP	TVSOP	DGV	48	2000	330.0	16.4	7.1	10.2	1.6	12.0	16.0	Q1

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### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CVMEH22501AIDGGREP	TSSOP	DGG	48	2000	346.0	346.0	41.0
CVMEH22501AIDGVREP	TVSOP	DGV	48	2000	346.0	346.0	33.0

### DGG (R-PDSO-G\*\*)

### PLASTIC SMALL-OUTLINE PACKAGE

### **48 PINS SHOWN**



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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